

# Octal 3-State Noninverting Buffer/Line Driver/Line Receiver

These octal buffers and line drivers and designed specifically to improve both the performance and density of three-state memory address drivers, clock drivers, and busoriented receivers and transmitters.

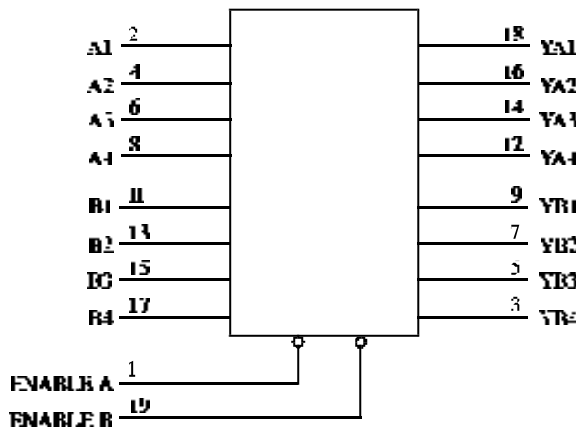
This devise features high fan-out, improved fan-in, and 400 mV noise margin.

It can be used to drive terminated lines down to 133 ohms.

- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- P-N-P Inputs Reduce D-C Loading
- Hysteresis at Inputs Improves Noise Margins



## LOGIC DIAGRAM



PIN 20 = V<sub>CC</sub>  
 PIN 10 = GND

## PIN ASSIGNMENT

ENABLE A	1	20	V <sub>CC</sub>
A1	2	19	ENABLE B
YB1	3	18	YA1
A2	4	17	B4
YB2	5	16	YA2
A3	6	15	B3
YB2	7	14	YA3
A4	8	13	B2
YB1	9	12	YA4
GND	10	11	B1

## FUNCTION TABLE

Inputs		Outputs
Enable A, Enable B	A,B	YA,YB
L	L	L
L	H	H
H	X	Z

X=don't care  
 Z = high impedance

# SL74LS244

## MAXIMUM RATINGS\*

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	7.0	V
V <sub>IN</sub>	Input Voltage	7.0	V
V <sub>OUT</sub>	Output Voltage	5.5	V
T <sub>stg</sub>	Storage Temperature Range	-65 to +150	°C

\*Maximum Ratings are those values beyond which damage to the device may occur. Functional operation should be restricted to the Recommended Operating Conditions.

## RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	Supply Voltage	4.75	5.25	V
V <sub>IH</sub>	High Level Input Voltage	2.0		V
V <sub>IL</sub>	Low Level Input Voltage		0.8	V
I <sub>OH</sub>	High Level Output Current		-15	mA
I <sub>OL</sub>	Low Level Output Current		24	mA
T <sub>A</sub>	Ambient Temperature Range	0	+70	°C

## DC ELECTRICAL CHARACTERISTICS over full operating conditions

Symbol	Parameter	Test Conditions	Guaranteed Limit		Unit
			Min	Max	
V <sub>IK</sub>	Input Clamp Voltage	V <sub>CC</sub> = min, I <sub>IN</sub> = -18 mA		-1.5	V
V <sub>OH</sub>	High Level Output Voltage	V <sub>CC</sub> = min, I <sub>OH</sub> = -1.0 mA	2.7		V
		V <sub>CC</sub> = min, I <sub>OH</sub> = -3.0 mA	2.4		
		V <sub>CC</sub> = min, I <sub>OH</sub> = -15 mA	2.0		
V <sub>OL</sub>	Low Level Output Voltage	V <sub>CC</sub> = min, I <sub>OL</sub> = 12 mA		0.4	V
		V <sub>CC</sub> = min, I <sub>OL</sub> = 24 mA		0.5	
V <sub>T+</sub> - V <sub>T-</sub>	Hysteresis	V <sub>CC</sub> = min	0.2		V
I <sub>OZH</sub>	Output Off Current HIGH	V <sub>CC</sub> = max, V <sub>OUT</sub> = 2.7 V		20	μA
I <sub>OZL</sub>	Output Off Current LOW	V <sub>CC</sub> = max, V <sub>OUT</sub> = 0.4 V		-20	μA
I <sub>IH</sub>	High Level Input Current	V <sub>CC</sub> = max, V <sub>IN</sub> = 2.7 V		20	μA
		V <sub>CC</sub> = max, V <sub>IN</sub> = 7.0 V		0.1	mA
I <sub>IL</sub>	Low Level Input Current	V <sub>CC</sub> = max, V <sub>IN</sub> = 0.4 V		-0.2	mA
I <sub>O</sub>	Output Short Circuit Current	V <sub>CC</sub> = max, V <sub>O</sub> = 0 V (Note 1)	-40	-225	mA
I <sub>CC</sub>	Supply Current	Outputs High	V <sub>CC</sub> = max	27	mA
		Outputs Low	Outputs open	46	
		All outputs disabled		54	



note 1: Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second

**AC ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5.0\text{ V}$ ,  $t_r = 15\text{ ns}$ ,  $t_f = 6.0\text{ ns}$ )

Symbol	Parameter	Test Condition	Min	Max	Unit
$t_{PLH}$	Propagation Delay, Data to Output	$C_L = 45\text{ pF}$ , $R_L = 667\ \Omega$		18	ns
$t_{PHL}$	Propagation Delay, Data to Output			18	ns
$t_{PZH}$	Output Enable Time			23	ns
$t_{PZL}$	Output Enable Time			30	ns
$t_{PHZ}$	Output Disable Time	$C_L = 5\text{ pF}$ $R_L = 667\ \Omega$		18	ns
$t_{PLZ}$	Output Disable Time			25	ns

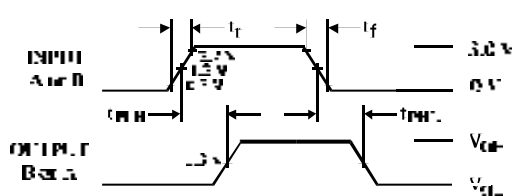
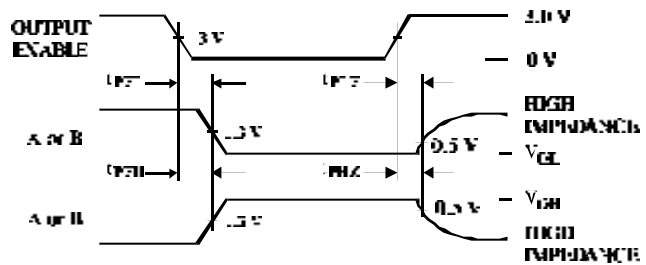
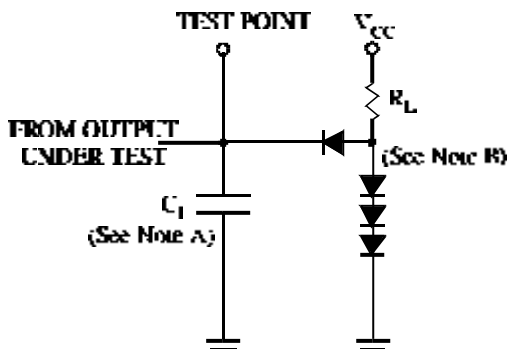


Figure 1. Switching Waveforms  
(See Figure 3)



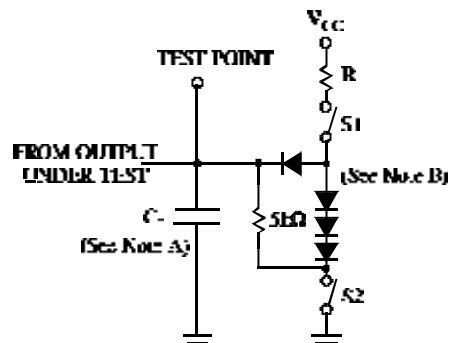
$t_{PZL}$  - S1 closed, S2 opened  
 $t_{PZH}$  - S1 opened, S2 closed  
 $t_{PLZ}$ ,  $t_{PHZ}$  - S1 and S2 closed

Figure 2. Switching Waveforms  
(See Figure 4)



NOTES A.  $C_L$  includes probe and jig capacitance.  
 B. All diodes are 1N916 or 1N3064.

Figure 3. Test Circuit



NOTES A.  $C_L$  includes probe and jig capacitance.  
 B. All diodes are 1N916 or 1N3064.

Figure 4. Test Circuit

EXPANDED LOGIC DIAGRAM

